

<b>Notice of References Cited</b>	Application/Control No. 10/714,153		Applicant(s)/Patent Under Reexamination JAIN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0205727	10-2004	Sit et al.	717/125
*	B	US-2004/0167896	08-2004	Eakin, William Joseph	707/010
*	C	US-2004/0220915	11-2004	Kline et al.	707/003
*	D	US-2002/0087915	07-2002	Perla et al.	714/15
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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#### FOREIGN PATENT DOCUMENTS

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	N					
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#### NON-PATENT DOCUMENTS

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